Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/757,227	DEWITT ET AL.
Examiner	Art Unit
Arpan P. Savla	2185

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INT	INTERFERENCE SEARCHED		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PALM and EAST Inventor name search	2/6/2006	A.S.
East search for references cited in IDS	2/6/2006	A.S.
East search of 711/118,125- 126,130,133-134,144-145,154- 156,159 (text search only, see search history printout)	2/6/2006	A.S.
East global text search (see search history printout)	2/6/2006	A.S.
Consulted Wil Grant in the 101 Help Panel	2/6/2006	A.S.
PLUS Search	2/7/2006	A.S.
Consulted Matthew Anderon for search help	2/8/2006	A.S.
IEEE Xplore text search (NPL)	2/8/2006	A.S.

Search Notes (con	tinued)

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	Subclass	Subclass Date

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Google text search (NPL)	2/8/2006	A.S.
Consulted Kevin Ellis for search help	2/13/2006	A.S.
Consulted Reginald Bragdon for search help	2/13/2006	A.S.
Consulted Matthew Anderson for search help	2/13/2006	A.S.
Fast & Focused Search (Geoffrey St. Leger)	2/13/2006	A.S.
IEEE Xplore text search (NPL)	2/14/2006	A.S.
Consulted Kevin Verbrugge for search help	2/15/2006	A.S.